DW PACKAGE

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- Low r_{DS(on)} . . . 0.4 Ω Typ
- Voltage Output . . . 60 V
- Input Protection Circuitry . . . 18 V
- Pulsed Current . . . 3 A Per Channel
- Extended ESD Capability . . . 4000 V
- Direct Logic-Level Interface

description

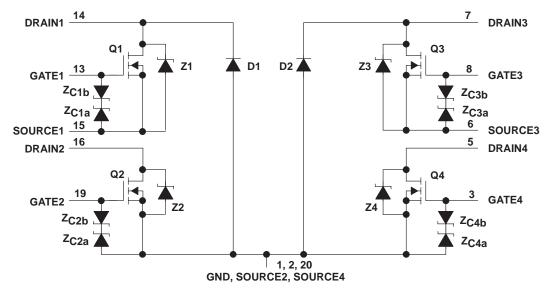
The TPIC5421L is a monolithic gate-protected logic-level power DMOS array that consists of four electrically isolated N-channel enhancement-mode DMOS transistors, two of which are configured with common source. Each transistor features integrated high-current zener diodes ($Z_{\rm CXa}$ and $Z_{\rm CXb}$) to prevent gate damage in the event that an overstress condition occurs. These zener diodes also provide up to 4000 V of ESD protection when tested using the human-body model of a 100-pF capacitor in series with a 1.5-k Ω resistor.

The TPIC5421L is offered in a 20-pin wide-body surface-mount (DW) package and a 16-pin thermally-enhanced dual-in-line (NE) package and is characterized for operation over the case temperature of -40°C to 125°C.

(TOP VIEW) 20 SOURCE2/GND **GND** 19 GATE2 SOURCE4/GND 18 NC GATE4 17 NC NC II 4 DRAIN4 II 5 16 DRAIN2 SOURCE3 [15 SOURCE1 DRAIN3 7 14 DRAIN1 GATE3 8 13 GATE1 12 NC NC II 9 NC 10 11 NC **NE PACKAGE** (TOP VIEW) DRAIN2 16 SOURCE1 SOURCE2/GND [15 DRAIN1 GATE2 3 14 GATE1 13 GND GND [GND [5 12 ∏ GND GATE4 11 GATE3 SOURCE4/GND [10 DRAIN3 DRAIN4 9 SOURCE3

NC - No internal connection

schematic



NOTE A: For correct operation, no terminal may be taken below GND. Pin numbers shown are for the DW package.

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absolute maximum ratings over operating case temperature range (unless otherwise noted)[†]

Drain-to-source voltage, V _{DS}	60 V
Source-to-GND voltage (Q1, Q3)	
Drain-to-GND voltage (Q1, Q3)	100 V
Drain-to-GND voltage (Q2, Q4)	60 V
Gate-to-source voltage range, V _{GS}	–9 V to 18 V
Continuous drain current, each output, T _C = 25°C: NE package	1.5 A
	1 A
Continuous source-to-drain diode current, T _C = 25°C	1 A
Pulsed drain current, each output, I _{max} , T _C = 25°C (see Note 1 and Figure 15)	3 A
Continuous gate-to-source zener-diode current, T _C = 25°C	±50 mA
Pulsed gate-to-source zener-diode current, T _C = 25°C	±500 mA
Single-pulse avalanche energy, E_{AS} , $T_{C} = 25^{\circ}C$ (see Figures 4 and 16)	180 mJ
Continuous total power dissipation	See Dissipation Rating Table
Operating virtual junction temperature range, T _{.J.}	–40°C to 150°C
Operating case temperature range, T _C	–40°C to 125°C
Storage temperature range, T _{Stq}	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: Pulse duration = 10 ms, duty cycle = 2%

DISSIPATION RATING TABLE

PACKAGE	T _C ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _C = 25°C	T _C = 125°C POWER RATING
DW	1125 mW	9.0 mW/°C	225 mW
NE	2075 mW	16.6 mW/°C	415 mW

electrical characteristics, $T_C = 25^{\circ}C$ (unless otherwise noted)

	PARAMETER	TEST COND	MIN	TYP	MAX	UNIT	
V _{(BR)DSX}	Drain-to-source breakdown voltage	$I_D = 250 \mu\text{A},$	$V_{GS} = 0$	60			V
V _{GS(th)}	Gate-to-source threshold voltage	I _D = 1 mA, See Figure 5	$V_{DS} = V_{GS}$	1.5	1.85	2.2	V
V(BR)GS	Gate-to-source breakdown voltage	IGS = 250 μA		18			V
V(BR)SG	Source-to-gate breakdown voltage	I _{SG} = 250 μA		9			V
V _(BR)	Reverse drain-to-GND breakdown voltage (across D1, D2)	Drain-to-GND curren	t = 250 μA	100			V
V _{DS(on)}	Drain-to-source on-state voltage	I _D = 1 A, See Notes 2 and 3	$V_{GS} = 5 V$,		0.4	0.475	V
V _{F(SD)}	Forward on-state voltage, source-to-drain	I _S = 1 A, V _{GS} = 0 (Z1, Z2, Z3, Z4), See Notes 2 and 3 and Figure 12			0.9	1.1	V
VF	Forward on-state voltage, GND-to-drain	I _D = 1 A (D1, D2), See Notes 2 and 3			4.6		V
	Zero-gate-voltage drain current	V _{DS} = 48 V, V _{GS} = 0	T _C = 25°C		0.05	1	
IDSS			T _C = 125°C		0.5	10	μΑ
IGSSF	Forward-gate current, drain short circuited to source	V _{GS} = 15 V,	$V_{DS} = 0$		20	200	nA
IGSSR	Reverse-gate current, drain short circuited to source	$V_{SG} = 5 V$,	$V_{DS} = 0$		10	100	nA
L	Leakage august drain to CND	$T_C = 25^{\circ}C$		0.05	1	^	
l _{lkg}	Leakage current, drain-to-GND	V _{DGND} = 48 V	T _C = 125°C		0.5	10	μΑ
*	Static drain-to-source on-state resistance	V _{GS} = 5 V, I _D = 1 A,	T _C = 25°C		0.4	0.475	Ω
rDS(on)	Static drain-to-source on-state resistance	See Notes 2 and 3 and Figures 6 and 7	T _C = 125°C		0.65	0.68	52
9fs	Forward transconductance	V _{DS} = 15 V, See Notes 2 and 3 ar	I _D = 0.5 A, nd Figure 9	1.25	1.4		S
C _{iss}	Short-circuit input capacitance, common source	1			220	275	
C _{oss}	Short-circuit output capacitance, common source	$V_{DS} = 25 \text{ V},$	$V_{GS} = 0$,	$V_{GS} = 0$,		150	pF
C _{rss}	Short-circuit reverse-transfer capacitance, common source	f = 1 MHz,			100	125	þг

NOTES: 2. Technique should limit $T_J - T_C$ to $10^{\circ}C$ maximum.

source-to-drain and GND-to-drain diode characteristics, $T_C = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS				TYP	MAX	UNIT
			Z1 and Z3		55			
t _{rr}	t _{rr} Reverse-recovery time	Is = 0.5 A,	V _{DS} = 48 V,	Z2 and Z4		150		ns
				D1 and D2		200		
	$V_{GS} = 0$, See Figures 1 at Q_{RR} Total diode charge	See Figures 1 and 14	di/dt = 100 A/μs, es 1 and 14	Z1 and Z3		0.06		
Q _{RR}				Z2 and Z4		0.3		μС
				D1 and D2		0.7		

^{3.} These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.

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resistive-load switching characteristics, $T_C = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT														
^t d(on)	Turn-on delay time					25	50															
td(off)	Turn-off delay time	$V_{DD} = 25 \text{ V}, \qquad R_{L} = 25 \Omega, \\ t_{f1} = 10 \text{ ns}, \qquad \text{See Figure 2}$	$t_{r1} = 10 \text{ ns},$		20	40																
t _{r2}	Rise time			See Figure 2	e 2		21	42	ns													
t _{f2}	Fall time]				9	18															
Qg	Total gate charge					3.9	5															
Q _{gs(th)}	Threshold gate-to-source charge	V _{DS} = 48 V, See Figure 3				-		-				-	-				$I_D = 0.5 A,$	$V_{GS} = 5 V$,		0.55	0.8	nC
Q _{gd}	Gate-to-drain charge							2.5	3.6													
L _D	Internal drain inductance					5		- II														
LS	Internal source inductance					5		nΗ														
Rg	Internal gate resistance					0.25		Ω														

thermal resistance

PARAMETER			TEST CONDITIONS	MIN	TYP	MAX	UNIT
D. Landing to embine the second of	lunation to ambient the annual mariatanes	DW package	Coo Notoo A and C	90			
$R_{\theta JA}$	Junction-to-ambient thermal resistance NE package See Notes 4 and	See Notes 4 and 6		60			
$R_{\theta JB}$	Junction-to-board thermal resistance	DW package	See Notes 4 and 6		53		°C/W
R ₀ JP Junction-to	Junction-to-pin thermal resistance	DW package	See Notes 5 and 6		30		
		NE package	See Notes 5 and 6		25		

NOTES: 4. Package mounted on an FR4 printed-circuit board with no heatsink.

5. Package mounted in intimate contact with infinite heatsink.

6. All outputs with equal power

PARAMETER MEASUREMENT INFORMATION

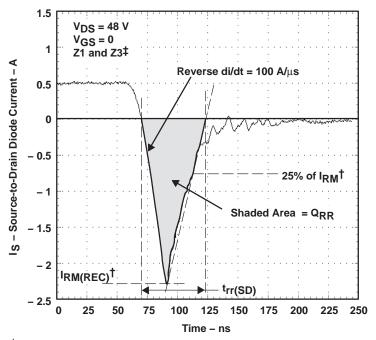
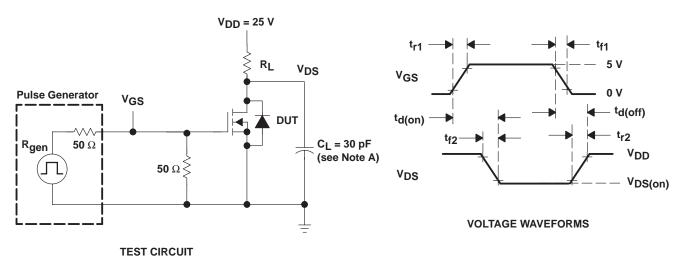


Figure 1. Reverse-Recovery-Current Waveforms of Source-to-Drain Diode



NOTE A: C_L includes probe and jig capacitance.

Figure 2. Resistive-Switching Test Circuit and Voltage Waveforms

 $[\]begin{tabular}{l} \uparrow I_{RM(REC)}$ = maximum recovery current \\ $\rlap/$ The above waveform is representative of Z2, Z4, D1, and D2 in shape only. \\ \end{tabular}$

PARAMETER MEASUREMENT INFORMATION

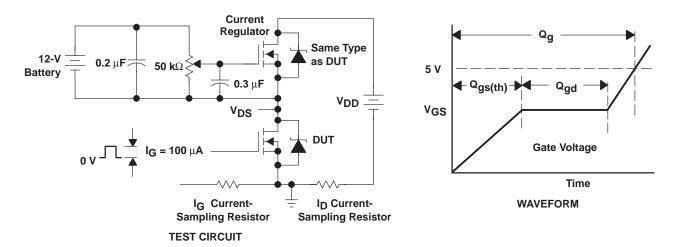
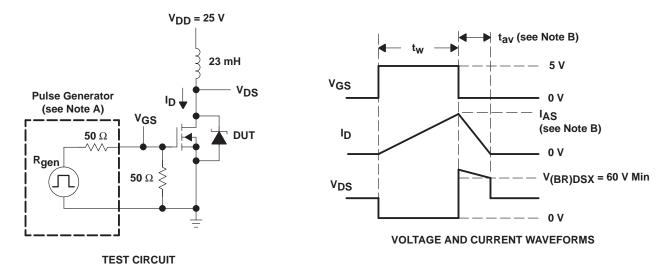


Figure 3. Gate-Charge Test Circuit and Waveform



- NOTES: A. The pulse generator has the following characteristics: $t_{\Gamma} \le 10$ ns, $t_{\Gamma} \le 10$ ns, $t_{\Omega} = 50 \ \Omega$.
 - B. Input pulse duration (t_W) is increased until peak current $I_{AS} = 3$ A.

Energy test level is defined as E_{AS} =
$$\frac{I_{AS} \times V_{(BR)DSX} \times t_{av}}{2}$$
 = 180 mJ, where t_{av} = avalanche time

Figure 4. Single-Pulse Avalanche-Energy Test Circuit and Waveforms

TYPICAL CHARACTERISTICS

GATE-TO-SOURCE THRESHOLD VOLTAGE

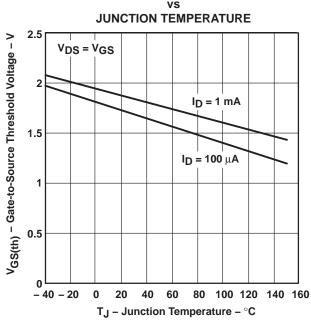


Figure 5

STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

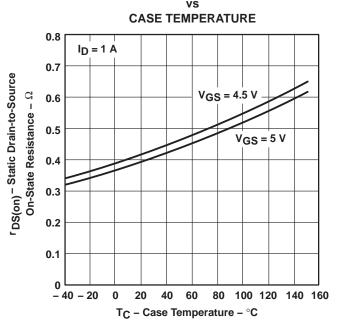


Figure 6

STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

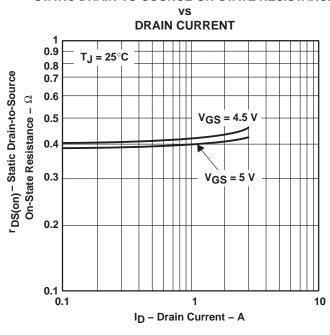


Figure 7

DRAIN CURRENT vs DRAIN-TO-SOURCE VOLTAGE

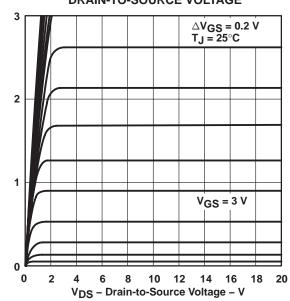


Figure 8

D- Drain Current - A

TYPICAL CHARACTERISTICS

3

2

0

 $T_J = 150^{\circ}C$ $T_J = 125^{\circ}C$

1

ID - Drain Current - A

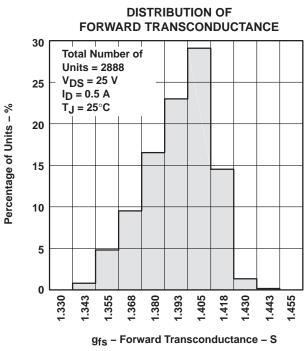


Figure 9

V_{GS} - Gate-to-Source Voltage - V

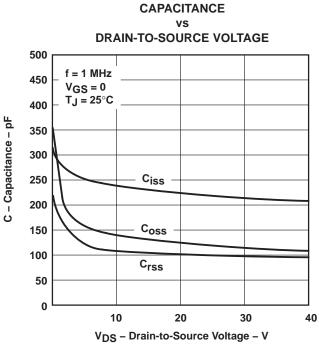
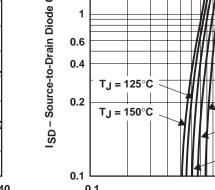


Figure 11



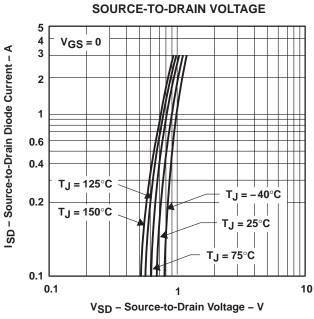


Figure 10

SOURCE-TO-DRAIN DIODE CURRENT

DRAIN CURRENT

GATE-TO-SOURCE VOLTAGE

 $T_J = -40^{\circ}C$

5

TJ = 25°C

 $T_J = 75^{\circ}C$

3

TYPICAL CHARACTERISTICS

DRAIN-TO-SOURCE VOLTAGE AND GATE-TO-SOURCE VOLTAGE

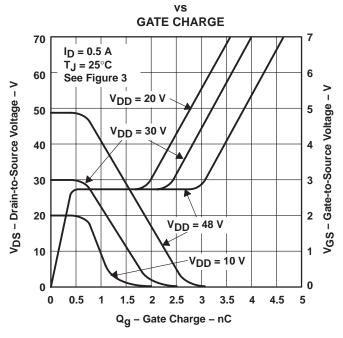


Figure 13

REVERSE-RECOVERY TIME

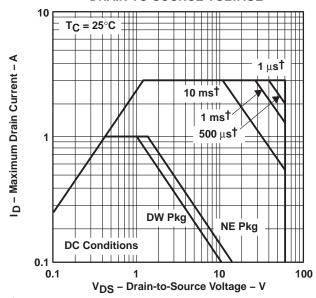
٧S REVERSE di/dt 200 $V_{DS} = 48 V$ $V_{GS} = 0$ 175 $I_{S} = 0.5 A$ trr - Reverse-Recovery Time - ns T_J = 25°C 150 See Figure 1 125 100 Z2 and Z4 75 50 Z1 and Z3 25 0 100 200 300 400 500 700 600 Reverse di/dt - A/µs

Figure 14



THERMAL INFORMATION

MAXIMUM DRAIN CURRENT vs DRAIN-TO-SOURCE VOLTAGE



†Less than 2% duty cycle

Figure 15

MAXIMUM PEAK AVALANCHE CURRENT vs TIME DURATION OF AVALANCHE

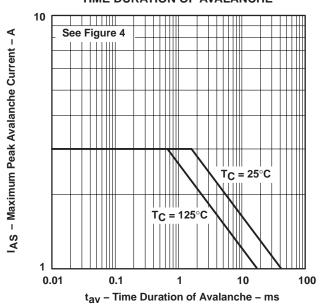
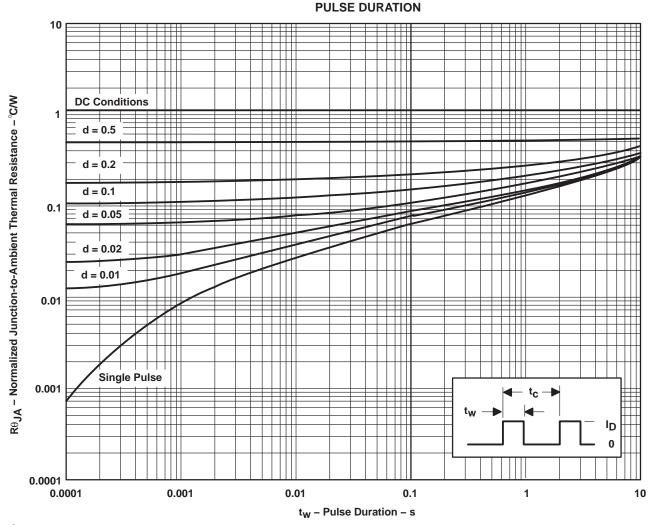


Figure 16

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THERMAL INFORMATION

NE PACKAGE[†] NORMALIZED JUNCTION-TO-AMBIENT THERMAL RESISTANCE vs



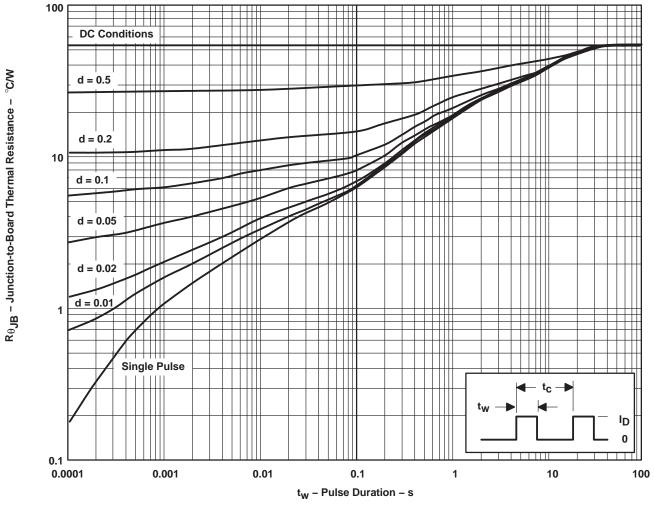
† Device mounted on FR4 printed-circuit board with no heatsink.

NOTES A: $Z_{\theta JA}(t) = r(t) R_{\theta JA}$ $t_W = \text{pulse duration}$ $t_C = \text{cycle time}$ $d = \text{duty cycle} = t_W/t_C$

Figure 17

THERMAL INFORMATION

DW PACKAGE† JUNCTION-TO-BOARD THERMAL RESISTANCE vs PULSE DURATION



† Device mounted on a 24 in², 4-layer FR4 printed-circuit board with no heatsink.

NOTES A: $Z_{\theta JB}(t) = r(t) R_{\theta JB}$ $t_W = \text{pulse duration}$ $t_C = \text{cycle time}$ $d = \text{duty cycle} = t_W/t_C$

Figure 18





PACKAGE OPTION ADDENDUM

8-Apr-2005

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
TPIC5421LDW	OBSOLETE	SOIC	DW	20	TBD	Call TI	Call TI
TPIC5421LNE	OBSOLETE	PDIP	NE	16	TBD	Call TI	Call TI

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in

a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

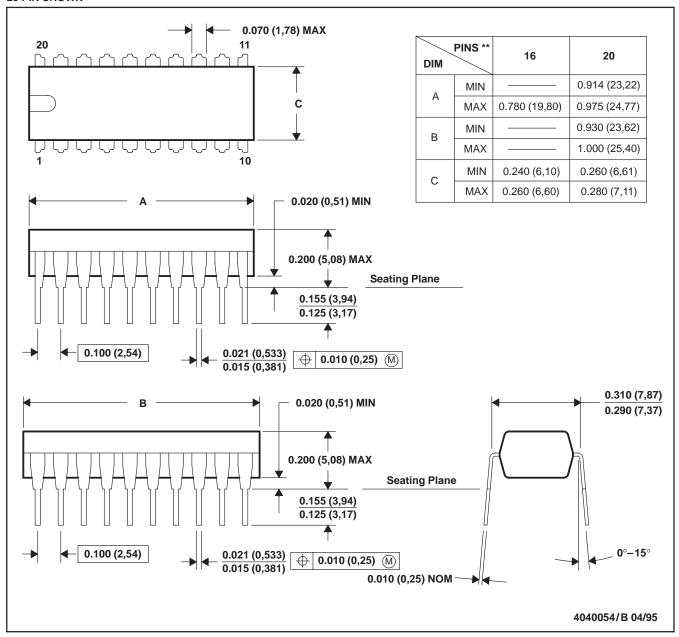
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NE (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

20 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-001 (16 pin only)



SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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